



The Testcenter facility 'LoRa<sup>®</sup> Test Lab' within IMST GmbH is recognized by the LoRa<sup>®</sup> Alliance for testing in accordance to the LoRaWAN<sup>®</sup> Specification V1.0.2

---

# **Report for Certification by Similarity according to LoRaWAN<sup>®</sup> V1.0.2**

for the Device

**“T45-LR“**

for the Customer

**“Landis+Gyr GmbH”**

Jens Lerner

Yavuz Turan

23<sup>rd</sup> January, 2023

## Administrative Summary

Location: IMST GmbH, Test Centre, Kamp-Lintfort, Germany

Responsible Test Engineer: Yavuz Turan, Jens Lerner

Subject: Test of Conformance to LoRaWAN® Specification V1.0.2

Company and Contact Information:

Landis+Gyr GmbH

Johannes Koch

Humboldtstr. 64

90459 Nuremberg

Germany

Checked Device: T45-LR

Hardware version: P000397970d (PCB Antenna)

Firmware version: 1.1

Type and Version of used Stack: 1.0.0, Semtech

Original End-device identifier: T45-LR-EXT

LoRa Device Class: A

LoRaWAN Specification version: V1.0.2

Certification requirements: LoRa End Device Certification by Similarity V1.1

Frequency band(s): 868 MHz

Type of Certification by Similarity:

Case 1: End-device certification using a certified module

Variant device differences to the referenced certified device:

- Same LoRa transceiver
- Same LoRaWAN protocol SW version
- Same MCU Core
- Same Clock design and implementation


Brief description of the differences between the primary and the variant device

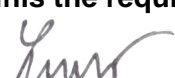
Internal antenna instead of external antenna

Date: 23<sup>rd</sup> January, 2023

The Test Report, No. 6230040 has the following conclusion:

**The device fulfils the requirements.**

Responsibility:   
Yavuz Turan  
Test Engineer

Approved:   
Jens Lerner  
Quality Engineer

Copyright Notice & Disclaimer: No part of this test report may be reproduced without written permission of IMST GmbH. The test results herein only refer to the tested sample. IMST GmbH cannot be made responsible for any generalizations or conclusions drawn from the test results presented herein concerning further samples of the tested device. Modification of the tested sample(s) is prohibited and leads to invalidity of this report.